

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	994	((dielectric or isolat\$4) adj3 (layer or coat\$4)) same (article or wafer or substrate or mask or reticle or object or target) same electrostatic\$4 same electrode	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 13:29
L2	900	((dielectric) adj3 (layer)) same (article or wafer or substrate or mask or reticle or object or target) same electrostatic\$4 same electrode	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 13:29
L3	177	2 and (clamp\$4 near9 (article or reticle or mask or wafer or substrate or object or target))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 13:30
L4	13	3 and ((detect\$4 or measur\$4 or sens\$4 or determin\$4) near5 (presence or absence) near5 (article or wafer or substrate or article or object or target))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 13:54
L5	33	3 and (protrusion or projection)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 14:50
L6	61	3 and (dielectric near9 (SiO or silic\$4 or SiN))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/29 14:59
L7	33	3 and 5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/29 14:59